

Amendment to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1. – 10. (cancelled)

11. (new) An inspection device comprising:
a storage means for storing image data obtained by imaging a specimen,
a display means for displaying said image data and an operation button,
an input means for receiving an operation by said operation button, and
a computer for classifying said image data according to a classification
category, wherein
said computer controls said display means so as to display
a category hierarchy display area being capable of displaying said
classification category of said specimen and a user category (sub class) arbitrarily
and selectively set corresponding to said classification category,
a first display area being capable of displaying plurality of said image data
corresponding to said classification category selected by said category hierarchy
display area, and

a second display area being capable of displaying plurality of said image data corresponding to said user category selected by said category hierarchy display area, and

said computer receives a moving operation of said image data from said first display area to said second display area from said input means, and stores said user category in an area where said image data is moved as that of said image data.

12. (new) An inspection device according to Claim 11, wherein
said second display area displayed on said display means by said computer is capable of displaying plurality of said image data corresponding to said user category selected by said hierarchy display area.

13. (new) An inspection device according to Claim 11, wherein
said computer controls said display means so as to display a third display area for displaying an enlarged image of said image data by receiving said image data selectively displayed on said first display area through said input means.

14. (new) An inspection device according to Claim 12, wherein
said enlarged image comprises a right side view, a left side view and a front view of said specimen.

15. (new) An inspection device according to Claim 11, wherein
said computer controls said display means so as to sequentially display a
system category display control MAP area for displaying all images loaded as
aggregation of points, and

plurality of said image data displayed in said first display area are a part of
said all of the imaged data loaded and are sequentially displayed, wherein
an identification mark for identifying a range of said first display area is
displayed on said system category display control MAP area.

16. (new) An inspection device according to Claim 11, wherein
said specimen is a semiconductor wafer and said classification category is
based on a classification of defects of said semiconductor wafer.

17. (new) An inspection device according to claim 12, wherein
said specimen is a semiconductor wafer and said classification category is
based on a classification of defects of said semiconductor wafer.

18. (new) An inspection device according to Claim 14, wherein
said specimen is a semiconductor wafer and said classification category is
based on a classification of defects of said semiconductor wafer.

19. (new) An inspection device according to Claim 11, wherein
size of said image data simultaneously displayed in said first display area is
more than 48 pixel and less than 70 pixel per one side.

20. (new) An inspection device according to Claim 11, wherein
row number of said image data capable of being simultaneously displayed in
said first display area is more than 6 and less than 9 pictorial images, and line
number of said image data capable of being simultaneously displayed in said first
display area is more than 6 and less than 9 pictorial images.